

Trench gate field-stop IGBT, M series 650 V, 6 A low loss

Datasheet - production data

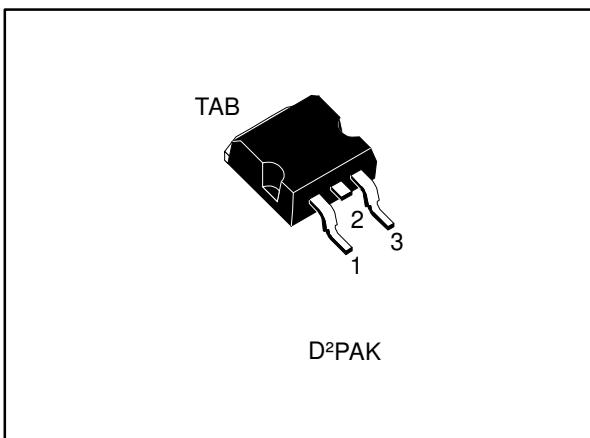
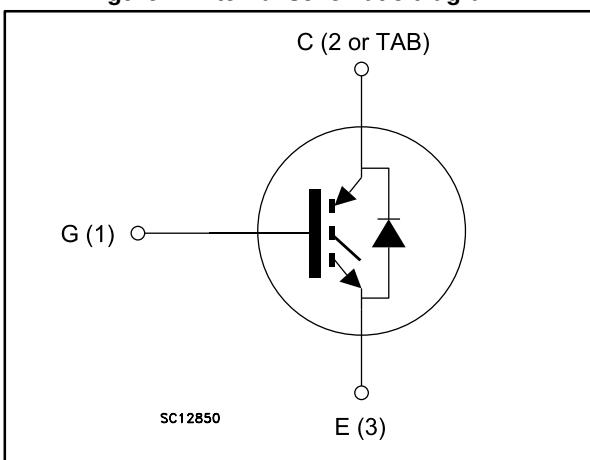


Figure 1: Internal schematic diagram



Features

- 6 μ s of short-circuit withstand time
- $V_{CE(sat)} = 1.55$ V (typ.) @ $I_C = 6$ A
- Tight parameter distribution
- Safer paralleling
- Low thermal resistance
- Soft and very fast recovery antiparallel diode

Applications

- Motor control
- UPS
- PFC

Description

This device is an IGBT developed using an advanced proprietary trench gate field-stop structure. The device is part of the M series IGBTs, which represent an optimal balance between inverter system performance and efficiency where low-loss and short-circuit functionality are essential. Furthermore, the positive $V_{CE(sat)}$ temperature coefficient and tight parameter distribution result in safer paralleling operation.

Table 1: Device summary

Order code	Marking	Package	Packing
STGB6M65DF2	G6M65DF2	D²PAK	Tape and reel

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1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{CES}	Collector-emitter voltage ($V_{GE} = 0$ V)	650	V
I_C	Continuous collector current at $T_C = 25$ °C	12	A
	Continuous collector current at $T_C = 100$ °C	6	A
$I_{CP}^{(1)}$	Pulsed collector current	24	A
V_{GE}	Gate-emitter voltage	± 20	V
I_F	Continuous forward current at $T_C = 25$ °C	12	A
	Continuous forward current at $T_C = 100$ °C	6	A
$I_{FP}^{(1)}$	Pulsed forward current	24	A
P_{TOT}	Total dissipation at $T_C = 25$ °C	88	W
T_{STG}	Storage temperature range	- 55 to 150	°C
T_J	Operating junction temperature range	- 55 to 175	°C

Notes:

(1)Pulse width limited by maximum junction temperature.

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance junction-case IGBT	1.7	°C/W
R_{thJC}	Thermal resistance junction-case diode	5	°C/W
R_{thJA}	Thermal resistance junction-ambient	62.5	°C/W

2 Electrical characteristics

$T_C = 25^\circ\text{C}$ unless otherwise specified

Table 4: Static characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)CES}$	Collector-emitter breakdown voltage	$V_{GE} = 0 \text{ V}, I_C = 250 \mu\text{A}$	650			V
$V_{CE(\text{sat})}$	Collector-emitter saturation voltage	$V_{GE} = 15 \text{ V}, I_C = 6 \text{ A}$		1.55	2.0	V
		$V_{GE} = 15 \text{ V}, I_C = 6 \text{ A}, T_J = 125^\circ\text{C}$		1.9		
		$V_{GE} = 15 \text{ V}, I_C = 6 \text{ A}, T_J = 175^\circ\text{C}$		2.1		
V_F	Forward on-voltage	$I_F = 6 \text{ A}$		2.2		V
		$I_F = 6 \text{ A}, T_J = 125^\circ\text{C}$		2.0		
		$I_F = 6 \text{ A}, T_J = 175^\circ\text{C}$		1.9		
$V_{GE(\text{th})}$	Gate threshold voltage	$V_{CE} = V_{GE}, I_C = 250 \mu\text{A}$	5	6	7	V
I_{CES}	Collector cut-off current	$V_{GE} = 0 \text{ V}, V_{CE} = 650 \text{ V}$			25	μA
I_{GES}	Gate-emitter leakage current	$V_{CE} = 0 \text{ V}, V_{GE} = \pm 20 \text{ V}$			± 250	μA

Table 5: Dynamic characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{ies}	Input capacitance	$V_{CE} = 25 \text{ V}, f = 1 \text{ MHz}, V_{GE} = 0 \text{ V}$	-	530	-	pF
C_{oes}	Output capacitance		-	31	-	
C_{res}	Reverse transfer capacitance		-	11	-	
Q_g	Total gate charge	$V_{CC} = 520 \text{ V}, I_C = 6 \text{ A}, V_{GE} = 15 \text{ V}$ (see <i>Figure 30: "Gate charge test circuit"</i>)	-	21.2	-	nC
Q_{ge}	Gate-emitter charge		-	5.2	-	
Q_{gc}	Gate-collector charge		-	8.8	-	

Table 6: IGBT switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{CE} = 400 \text{ V}, I_C = 6 \text{ A}, V_{GE} = 15 \text{ V}, R_G = 22 \Omega$ (see <i>Figure 29: "Test circuit for inductive load switching"</i>)	-	15	-	ns
t_r	Current rise time		-	5.8	-	ns
$(di/dt)_{on}$	Turn-on current slope		-	828	-	A/ μ s
$t_{d(off)}$	Turn-off-delay time		-	90	-	ns
t_f	Current fall time		-	130	-	ns
$E_{on}^{(1)}$	Turn-on switching energy		-	0.036	-	mJ
$E_{off}^{(2)}$	Turn-off switching energy		-	0.200	-	mJ
E_{ts}	Total switching energy		-	0.236	-	mJ
$t_{d(on)}$	Turn-on delay time	$V_{CE} = 400 \text{ V}, I_C = 6 \text{ A}, V_{GE} = 15 \text{ V}, R_G = 22 \Omega$ $T_J = 175 \text{ }^\circ\text{C}$ (see <i>Figure 29: "Test circuit for inductive load switching"</i>)	-	17	-	ns
t_r	Current rise time		-	7	-	ns
$(di/dt)_{on}$	Turn-on current slope		-	685	-	A/ μ s
$t_{d(off)}$	Turn-off-delay time		-	86	-	ns
t_f	Current fall time		-	205	-	ns
$E_{on}^{(1)}$	Turn-on switching energy		-	0.064	-	mJ
$E_{off}^{(2)}$	Turn-off switching energy		-	0.290	-	mJ
E_{ts}	Total switching energy		-	0.354	-	mJ
t_{sc}	Short-circuit withstand time	$V_{CC} \leq 400 \text{ V}, V_{GE} = 15 \text{ V}, T_{Jstart} = 150 \text{ }^\circ\text{C}$	6		-	μ s
		$V_{CC} \leq 400 \text{ V}, V_{GE} = 13 \text{ V}, T_{Jstart} = 150 \text{ }^\circ\text{C}$	10		-	μ s

Notes:

(1) Turn-on switching energy includes reverse recovery of the diode.

(2) Turn-off switching energy also includes the tail of the collector current.

Table 7: Diode switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
t_{rr}	Reverse recovery time	$I_F = 6 \text{ A}, V_R = 400 \text{ V}, V_{GE} = 15 \text{ V}$ (see <i>Figure 29: "Test circuit for inductive load switching"</i>) $di/dt = 1000 \text{ A}/\mu\text{s}$	-	140		ns
Q_{rr}	Reverse recovery charge		-	210		nC
I_{rrm}	Reverse recovery current		-	6.6		A
dI_{rr}/dt	Peak rate of fall of reverse recovery current during t_b		-	430		$\text{A}/\mu\text{s}$
E_{rr}	Reverse recovery energy		-	16		μJ
t_{rr}	Reverse recovery time	$I_F = 6 \text{ A}, V_R = 400 \text{ V}, V_{GE} = 15 \text{ V}$ $T_J = 175 \text{ }^\circ\text{C}$ (see <i>Figure 29: "Test circuit for inductive load switching"</i>) $di/dt = 1000 \text{ A}/\mu\text{s}$	-	200		ns
Q_{rr}	Reverse recovery charge		-	473		nC
I_{rrm}	Reverse recovery current		-	9.6		A
dI_{rr}/dt	Peak rate of fall of reverse recovery current during t_b		-	428		$\text{A}/\mu\text{s}$
E_{rr}	Reverse recovery energy		-	32		μJ

2.1 Electrical characteristics (curves)

Figure 2: Power dissipation vs. case temperature

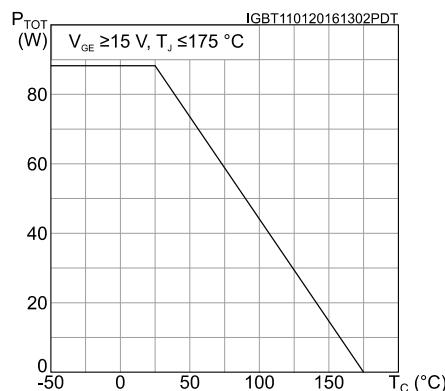


Figure 3: Collector current vs. case temperature

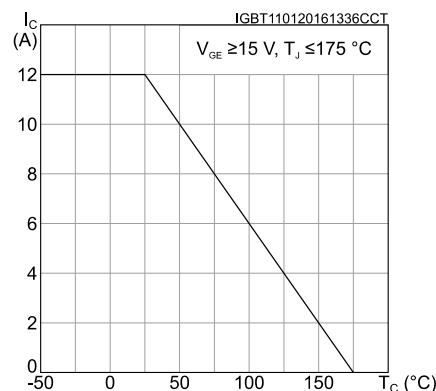


Figure 4: Output characteristics ($T_j = 25$ °C)

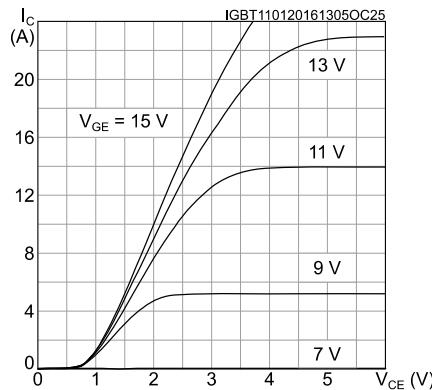


Figure 5: Output characteristics ($T_j = 175$ °C)

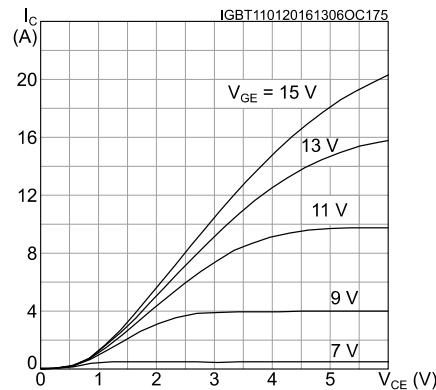


Figure 6: $V_{CE(sat)}$ vs. junction temperature

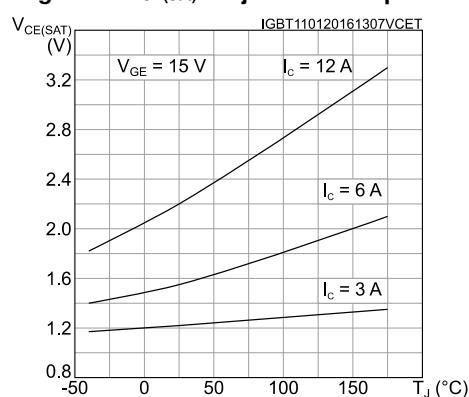
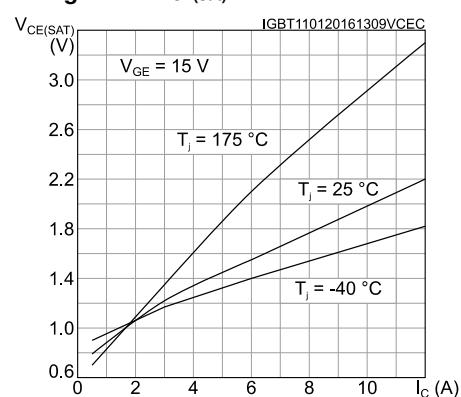


Figure 7: $V_{CE(sat)}$ vs. collector current



Electrical characteristics

STGB6M65DF2

Figure 8: Collector current vs. switching frequency

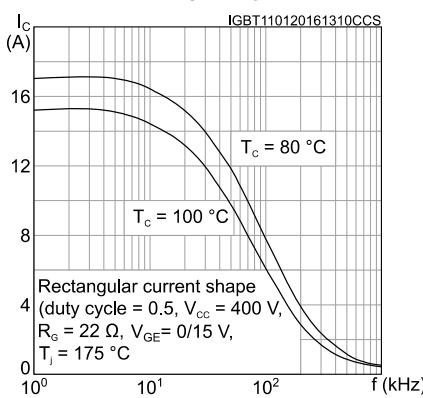


Figure 9: Forward bias safe operating area

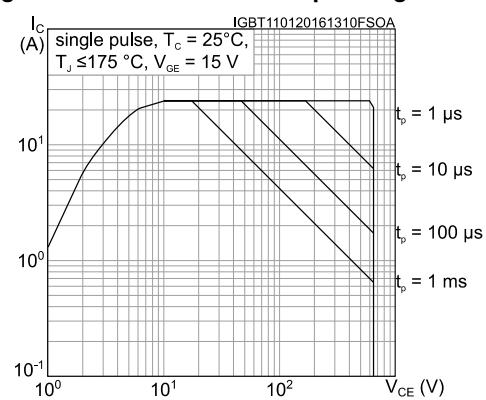


Figure 10: Transfer characteristics

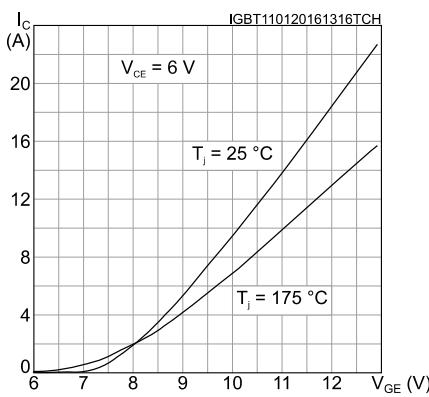


Figure 11: Diode V_F vs. forward current

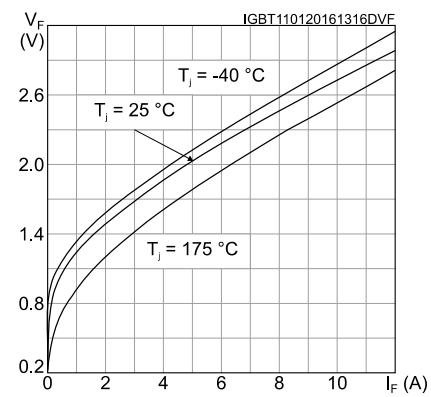


Figure 12: Normalized $V_{GE(th)}$ vs. junction temperature

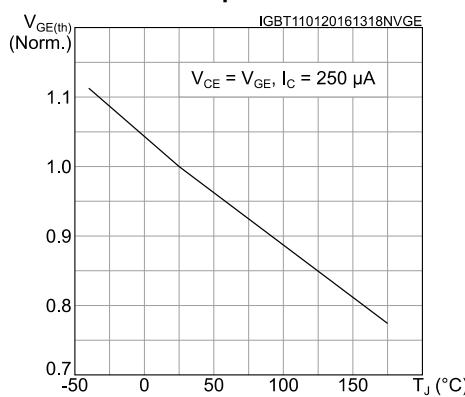


Figure 13: Normalized $V_{(BR)CES}$ vs. junction temperature

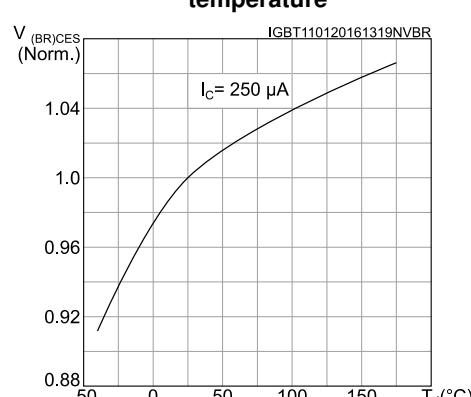


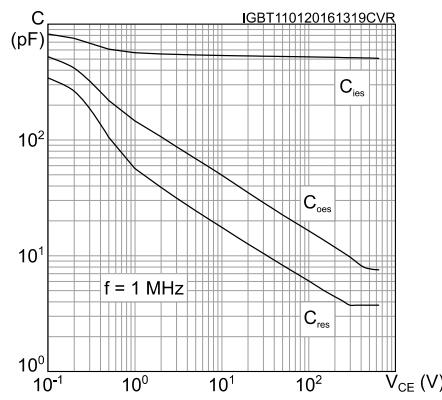
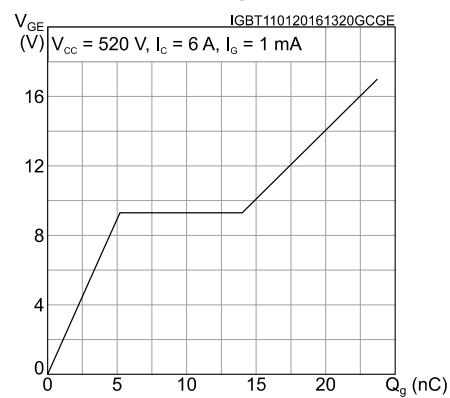
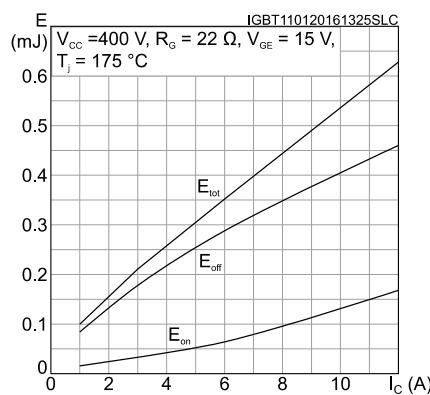
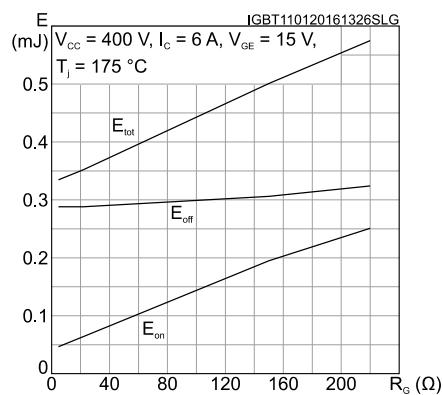
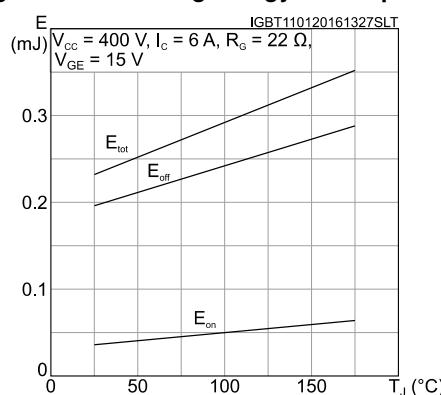
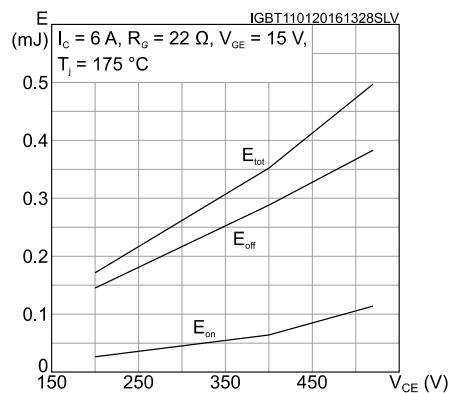
Figure 14: Capacitance variations**Figure 15: Gate charge vs. gate-emitter voltage****Figure 16: Switching energy vs. collector current****Figure 17: Switching energy vs. gate resistance****Figure 18: Switching energy vs. temperature****Figure 19: Switching energy vs. collector-emitter voltage**

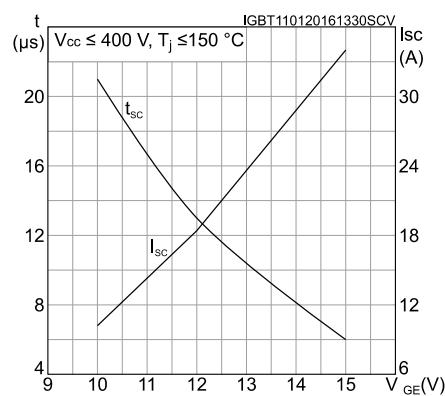
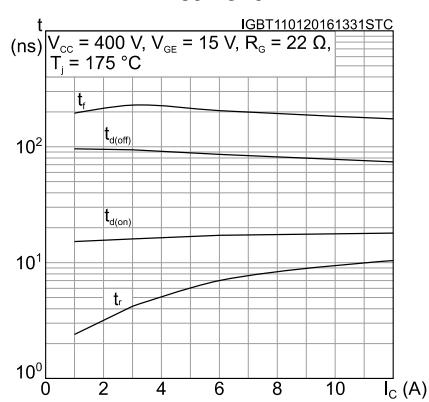
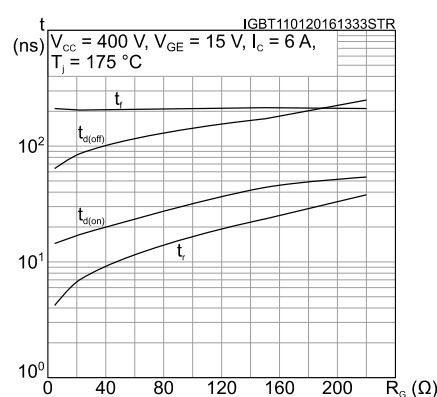
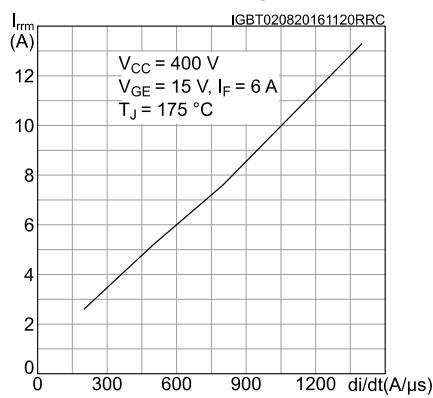
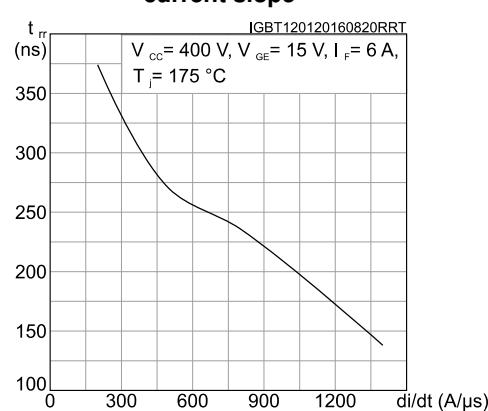
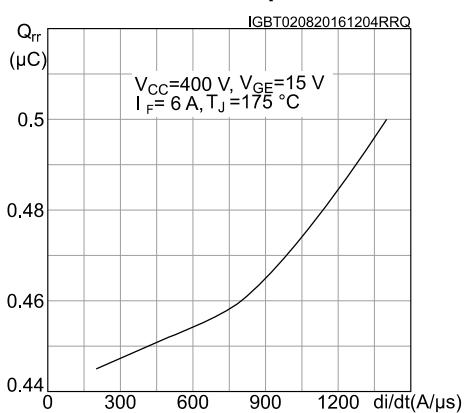
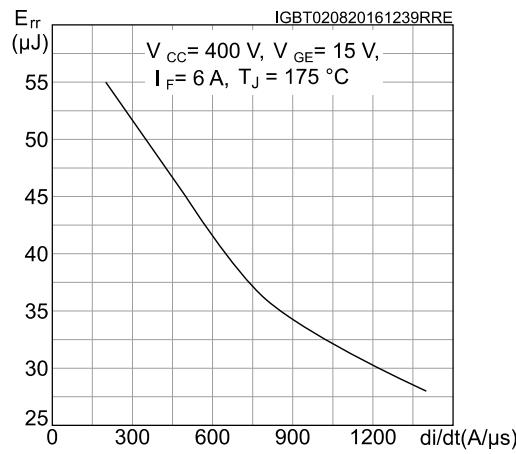
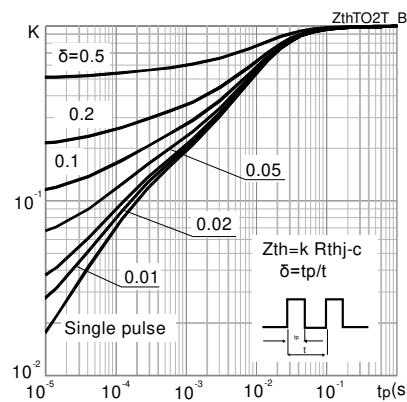
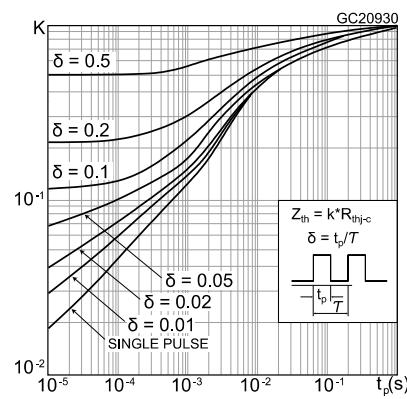
Figure 20: Short-circuit time and current vs. V_{GE} **Figure 21: Switching times vs. collector current****Figure 22: Switching times vs. gate resistance****Figure 23: Reverse recovery current vs. diode current slope****Figure 24: Reverse recovery time vs. diode current slope****Figure 25: Reverse recovery charge vs. diode current slope**

Figure 26: Reverse recovery energy vs. diode current slope**Figure 27: Thermal impedance for IGBT****Figure 28: Thermal impedance for diode**

3 Test circuits

Figure 29: Test circuit for inductive load switching

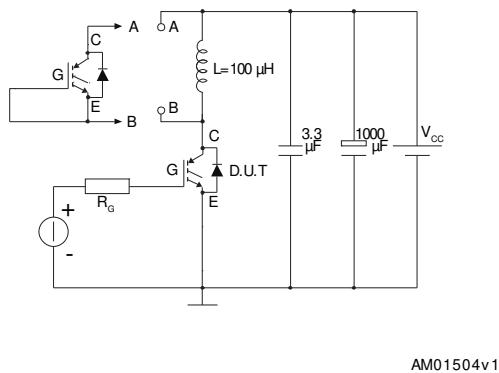


Figure 30: Gate charge test circuit

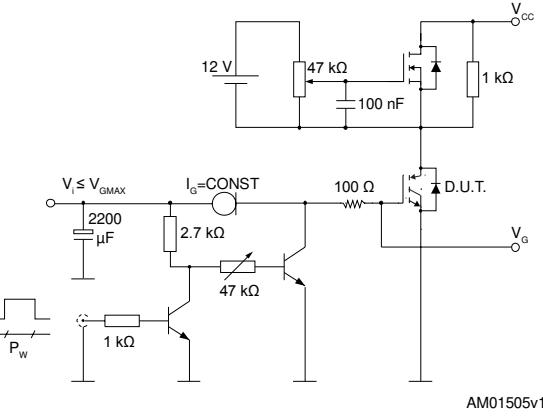
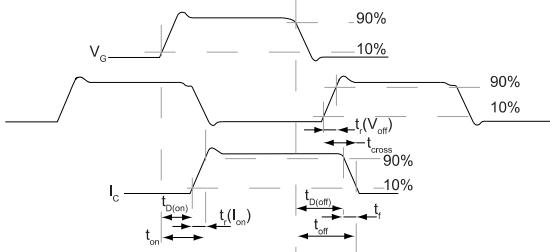
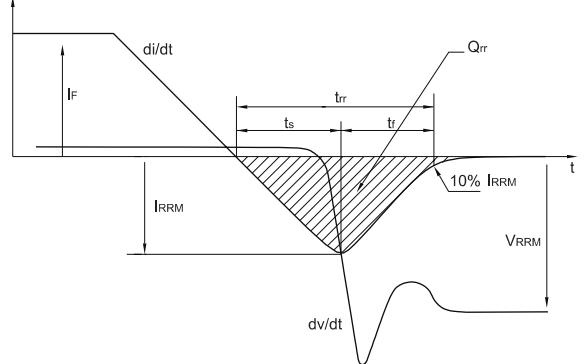


Figure 31: Switching waveform



AM01506v1

Figure 32: Diode reverse recovery waveform



4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.
ECOPACK® is an ST trademark.

4.1 D²PAK (TO-263) type A package information

Figure 33: D²PAK (TO-263) type A package outline

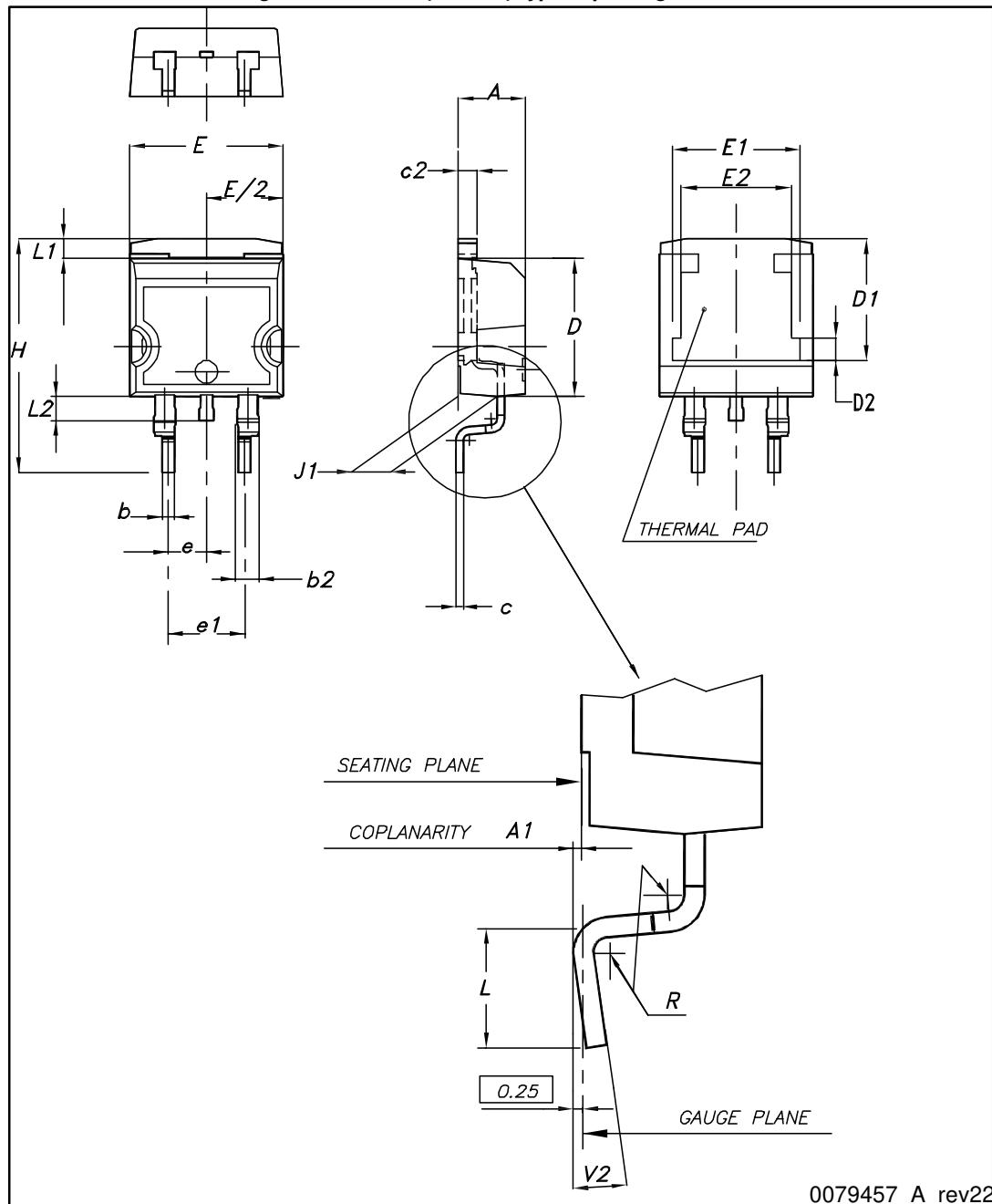
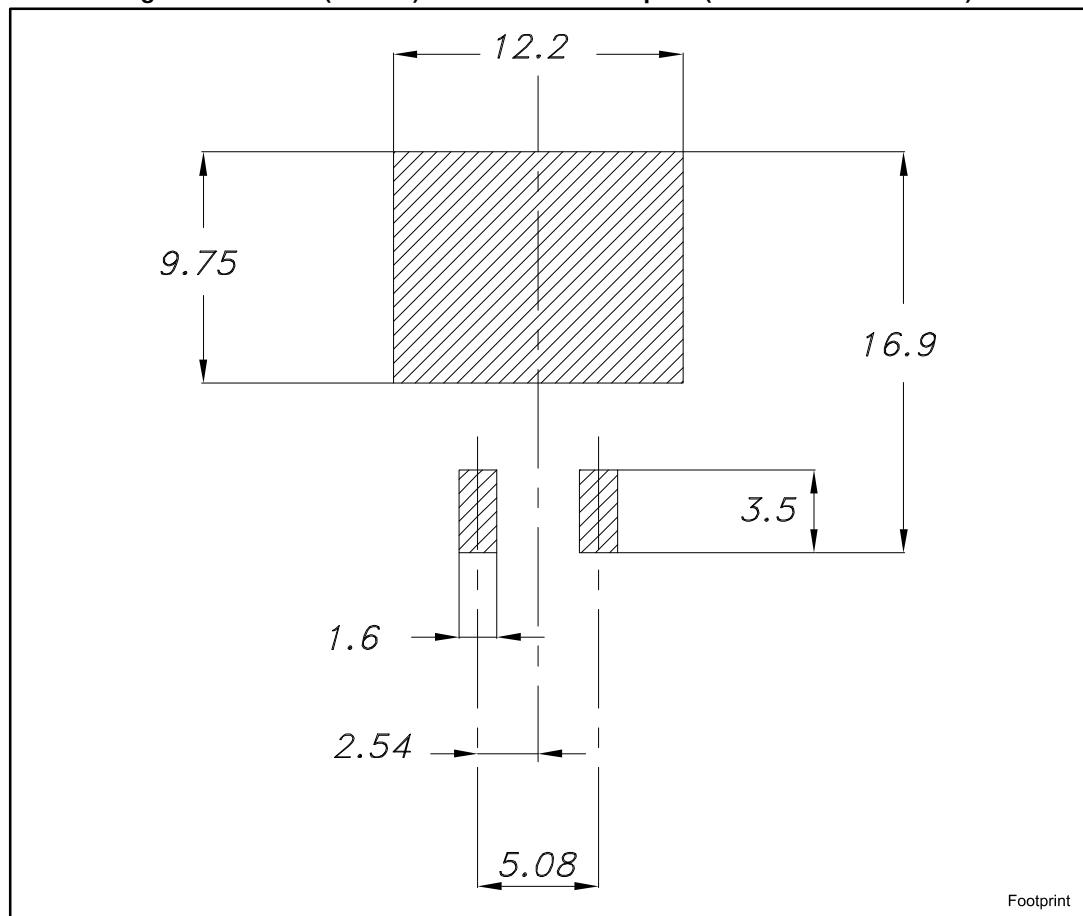


Table 8: D²PAK (TO-263) type A package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
A1	0.03		0.23
b	0.70		0.93
b2	1.14		1.70
c	0.45		0.60
c2	1.23		1.36
D	8.95		9.35
D1	7.50	7.75	8.00
D2	1.10	1.30	1.50
E	10		10.40
E1	8.50	8.70	8.90
E2	6.85	7.05	7.25
e		2.54	
e1	4.88		5.28
H	15		15.85
J1	2.49		2.69
L	2.29		2.79
L1	1.27		1.40
L2	1.30		1.75
R		0.4	
V2	0°		8°

Figure 34: D²PAK (TO-263) recommended footprint (dimensions are in mm)

4.2 D²PAK packing information

Figure 35: Tape outline

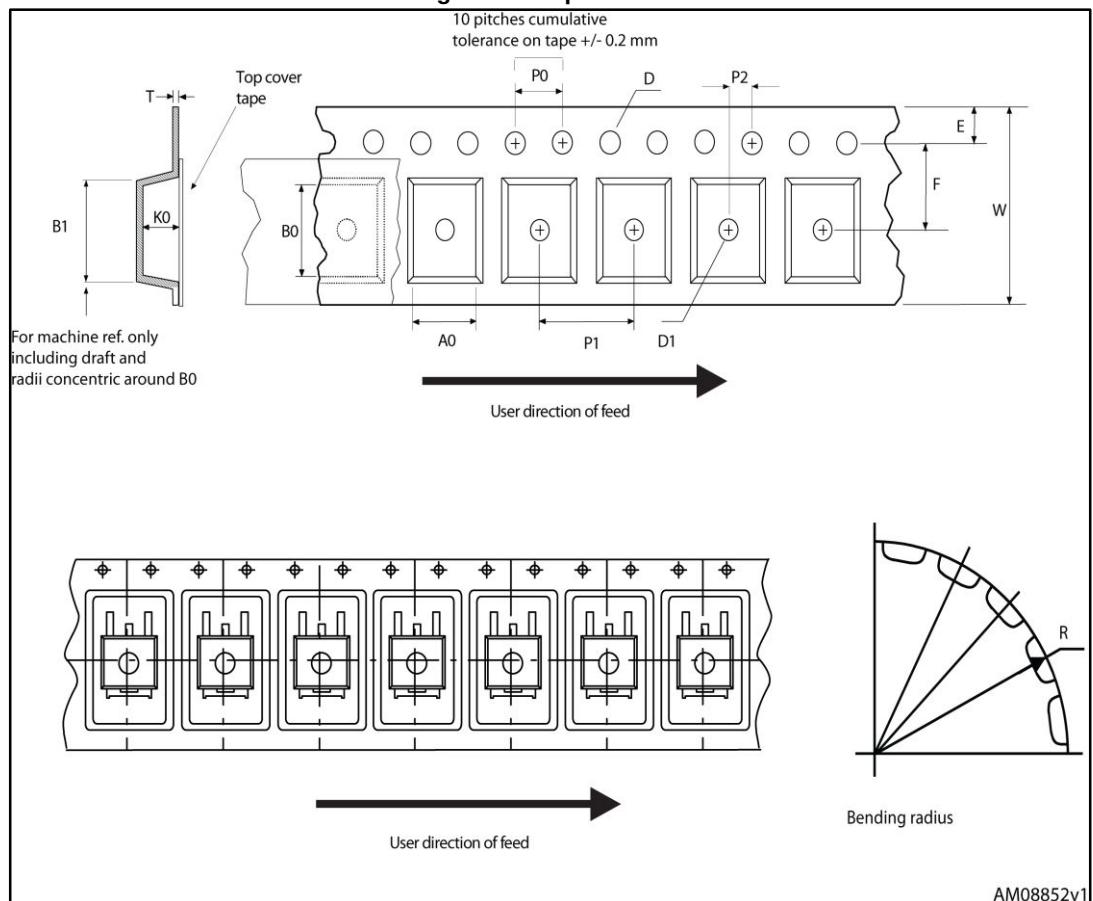
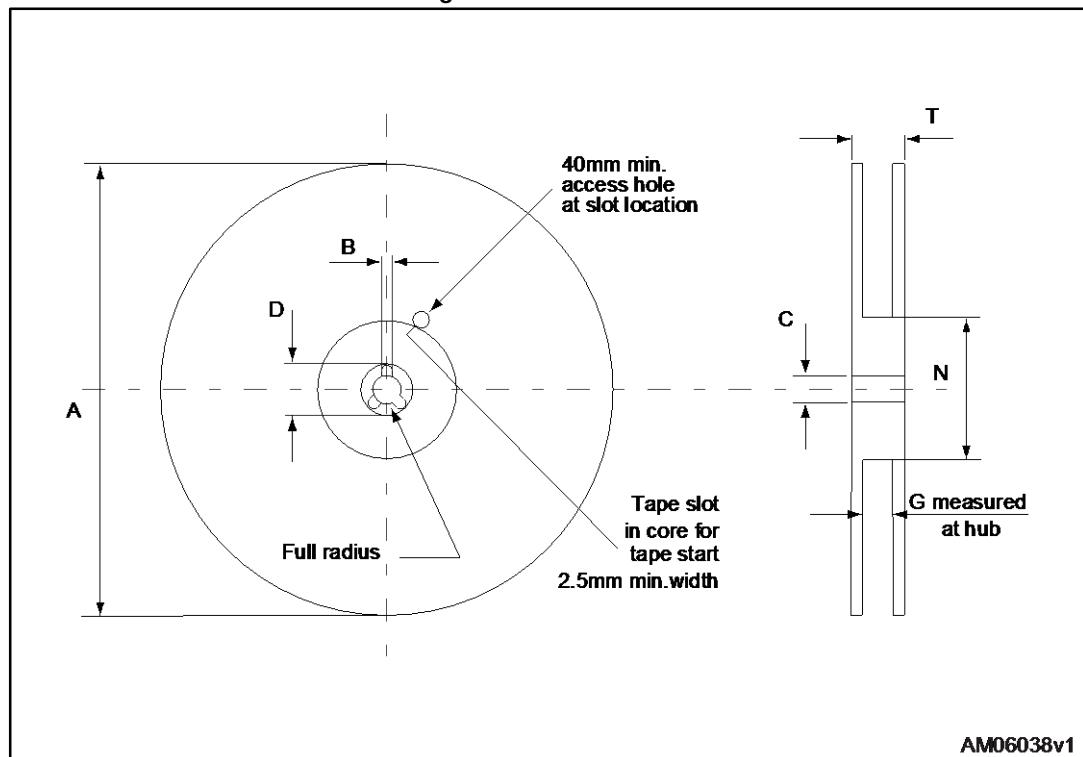


Figure 36: Reel outline

Table 9: D²PAK tape and reel mechanical data

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	10.5	10.7	A		330
B0	15.7	15.9	B	1.5	
D	1.5	1.6	C	12.8	13.2
D1	1.59	1.61	D	20.2	
E	1.65	1.85	G	24.4	26.4
F	11.4	11.6	N	100	
K0	4.8	5.0	T		30.4
P0	3.9	4.1			
P1	11.9	12.1	Base quantity		1000
P2	1.9	2.1	Bulk quantity		1000
R	50				
T	0.25	0.35			
W	23.7	24.3			

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
30-Nov-2015	1	First release.
13-Jan-2016	2	Modified: <i>Table 4: "Static characteristics"</i> , <i>Table 5: "Dynamic characteristics"</i> , <i>Table 6: "IGBT switching characteristics (inductive load)"</i> , and <i>Table 7: "Diode switching characteristics (inductive load)"</i> Added: <i>Section 2.1: "Electrical characteristics (curves)"</i> Minor text changes.
02-Aug-2016	3	Updated <i>Table 2: "Absolute maximum ratings"</i> , <i>Table 4: "Static characteristics"</i> , <i>Table 6: "IGBT switching characteristics (inductive load)"</i> , <i>Table 7: "Diode switching characteristics (inductive load)"</i> . Updated <i>Figure 9: "Forward bias safe operating area"</i> , <i>Figure 12: "Normalized VGE(th) vs. junction temperature"</i> , <i>Figure 20: "Short-circuit time and current vs. VGE"</i> , <i>Figure 23: "Reverse recovery current vs. diode current slope"</i> . Changed <i>Figure 25: "Reverse recovery charge vs. diode current slope"</i> and <i>Figure 26: "Reverse recovery energy vs. diode current slope"</i> .

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